

Background

Tao Luo received the B.Eng. degree in telecommunication engineering from the University of Electronic and Science Technology of China, Chengdu, China, in 2002. From 2002 to 2003, he worked with Huawei Technologies Company Ltd., where he was a Research and Development Engineer in the Central Software Research Department. Since 2003, he has been working toward the Ph.D. degree in Center of Integrated Circuit Failure Analysis, Electrical and Computer Engineering Department at the National University of Singapore, Singapore.

Academic Award

“Best Paper in Failure Analysis”, International Symposium on the Physical and Failure Analysis of Integrated Circuits (IPFA) 2005. For the paper "Transmission EELS Attachment for SEM" co-authored with associate professor Anjam Khursheed. This conference paper presents a new method of aberration correction for miniaturized spectrometer.

IPFA Best Paper Awards

During its gradual evolution, IPFA has developed a vision to be the Asian counterpart to corresponding conferences such as IRPS and ISTFA in the USA, and ESREF in Europe. The IPFA Best Paper award for the best technical paper presented in the conference was initiated at IPFA 1997. Subsequently, a Best Paper exchange with ISTFA was initiated in 1999, with the IPFA 1999 Best Paper being presented at ISTFA 2000 and the ISTFA 2000 Best Paper reciprocating at IPFA the following year. A similar Best Paper exchange was initiated with ESREF in 2000-2001. Currently, IPFA selects a Best Paper each for Failure Analysis and Reliability for exchange with ISTFA and ESREF respectively.

